



**ALPHA & OMEGA**  
SEMICONDUCTOR

**AON6548**

**30V N-Channel AlphaMOS**

### General Description

- Latest Trench Power AlphaMOS (αMOS LV) technology
- Very Low  $R_{DS(ON)}$  at 4.5V  $V_{GS}$
- Low Gate Charge
- High Current Capability
- RoHS and Halogen-Free Compliant

### Application

- DC/DC Converters in Computing, Servers, and POL
- Isolated DC/DC Converters in Telecom and Industrial

### Product Summary

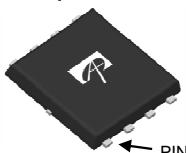
$V_{DS}$	30V
$I_D$ (at $V_{GS}=10V$ )	85A
$R_{DS(ON)}$ (at $V_{GS}=10V$ )	< 1.8mΩ
$R_{DS(ON)}$ (at $V_{GS}=4.5V$ )	< 2.5mΩ

100% UIS Tested  
100%  $R_g$  Tested

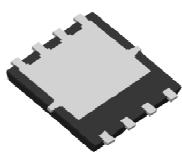


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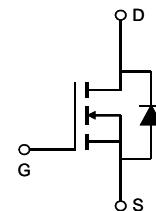
Top View



Bottom View



Top View



### Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	$V_{DS}$	30	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current <sup>G</sup>	$I_D$	85	A
$T_C=100^\circ C$		66	
Pulsed Drain Current <sup>C</sup>	$I_{DM}$	340	
Continuous Drain Current	$I_{DSM}$	52	A
$T_A=70^\circ C$		42	
Avalanche Current <sup>C</sup>	$I_{AS}$	60	A
Avalanche energy $L=0.1mH$ <sup>C</sup>	$E_{AS}$	180	mJ
$V_{DS}$ Spike	$V_{SPIKE}$	36	V
Power Dissipation <sup>B</sup>	$P_D$	83	W
$T_C=100^\circ C$		33	
Power Dissipation <sup>A</sup>	$P_{DSM}$	7.4	W
$T_A=70^\circ C$		4.7	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	°C

### Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$R_{θJA}$	14	17	°C/W
Maximum Junction-to-Ambient <sup>A,D</sup>		40	55	°C/W
Maximum Junction-to-Case	$R_{θJC}$	1.1	1.5	°C/W

**Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$\text{ID}=250\mu\text{A}, \text{V}_{\text{GS}}=0\text{V}$	30			V
$\text{I}_{\text{DSS}}$	Zero Gate Voltage Drain Current	$\text{V}_{\text{DS}}=30\text{V}, \text{V}_{\text{GS}}=0\text{V}$ $T_J=125^\circ\text{C}$			1 5	$\mu\text{A}$
$\text{I}_{\text{GSS}}$	Gate-Body leakage current	$\text{V}_{\text{DS}}=0\text{V}, \text{V}_{\text{GS}}=\pm20\text{V}$			$\pm100$	nA
$\text{V}_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$\text{V}_{\text{DS}}=\text{V}_{\text{GS}}, \text{I}_{\text{D}}=250\mu\text{A}$	1.4	1.8	2.2	V
$\text{R}_{\text{DS}(\text{ON})}$	Static Drain-Source On-Resistance	$\text{V}_{\text{GS}}=10\text{V}, \text{I}_{\text{D}}=20\text{A}$ $T_J=125^\circ\text{C}$		1.4 2	1.8 2.5	$\text{m}\Omega$
		$\text{V}_{\text{GS}}=4.5\text{V}, \text{I}_{\text{D}}=20\text{A}$		2	2.5	$\text{m}\Omega$
$\text{g}_{\text{FS}}$	Forward Transconductance	$\text{V}_{\text{DS}}=5\text{V}, \text{I}_{\text{D}}=20\text{A}$		125		S
$\text{V}_{\text{SD}}$	Diode Forward Voltage	$\text{I}_{\text{S}}=1\text{A}, \text{V}_{\text{GS}}=0\text{V}$		0.65	1	V
$\text{I}_{\text{S}}$	Maximum Body-Diode Continuous Current <sup>G</sup>				85	A
<b>DYNAMIC PARAMETERS</b>						
$\text{C}_{\text{iss}}$	Input Capacitance	$\text{V}_{\text{GS}}=0\text{V}, \text{V}_{\text{DS}}=15\text{V}, \text{f}=1\text{MHz}$		4290		pF
$\text{C}_{\text{oss}}$	Output Capacitance			1680		pF
$\text{C}_{\text{rss}}$	Reverse Transfer Capacitance			300		pF
$\text{R}_g$	Gate resistance	$\text{V}_{\text{GS}}=0\text{V}, \text{V}_{\text{DS}}=0\text{V}, \text{f}=1\text{MHz}$	0.4	0.8	1.2	$\Omega$
<b>SWITCHING PARAMETERS</b>						
$\text{Q}_g(10\text{V})$	Total Gate Charge	$\text{V}_{\text{GS}}=10\text{V}, \text{V}_{\text{DS}}=15\text{V}, \text{I}_{\text{D}}=20\text{A}$		65.2	90	nC
$\text{Q}_g(4.5\text{V})$	Total Gate Charge			31.2	45	nC
$\text{Q}_{\text{gs}}$	Gate Source Charge			12.6		nC
$\text{Q}_{\text{gd}}$	Gate Drain Charge			14.6		nC
$t_{\text{D}(\text{on})}$	Turn-On Delay Time	$\text{V}_{\text{GS}}=10\text{V}, \text{V}_{\text{DS}}=15\text{V}, \text{R}_{\text{L}}=0.75\Omega, \text{R}_{\text{GEN}}=3\Omega$		11		ns
$t_r$	Turn-On Rise Time			9.8		ns
$t_{\text{D}(\text{off})}$	Turn-Off Delay Time			38.8		ns
$t_f$	Turn-Off Fall Time			11.5		ns
$t_{\text{rr}}$	Body Diode Reverse Recovery Time	$\text{I}_{\text{F}}=20\text{A}, \text{dI}/\text{dt}=500\text{A}/\mu\text{s}$		23.5		ns
$\text{Q}_{\text{rr}}$	Body Diode Reverse Recovery Charge	$\text{I}_{\text{F}}=20\text{A}, \text{dI}/\text{dt}=500\text{A}/\mu\text{s}$		60		nC

A. The value of  $\text{R}_{\text{JJA}}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The Power dissipation  $P_{\text{DSM}}$  is based on  $\text{R}_{\text{JJA}} \leq 10\text{s}$  and the maximum allowed junction temperature of  $150^\circ\text{C}$ . The value in any given application depends on the user's specific board design.

B. The power dissipation  $P_D$  is based on  $T_{\text{J(MAX)}}=150^\circ\text{C}$ , using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Single pulse width limited by junction temperature  $T_{\text{J(MAX)}}=150^\circ\text{C}$ .

D. The  $\text{R}_{\text{JJA}}$  is the sum of the thermal impedance from junction to case  $\text{R}_{\text{JJC}}$  and case to ambient.

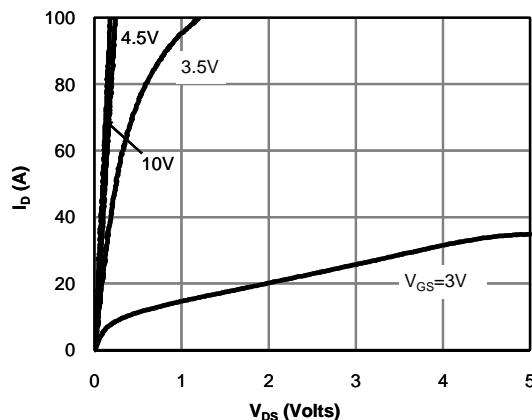
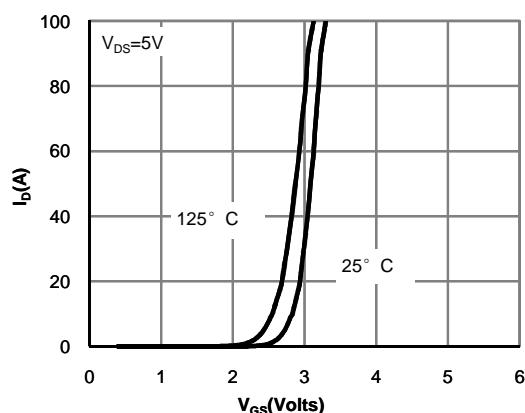
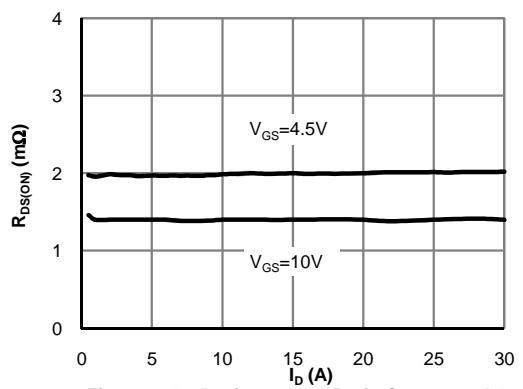
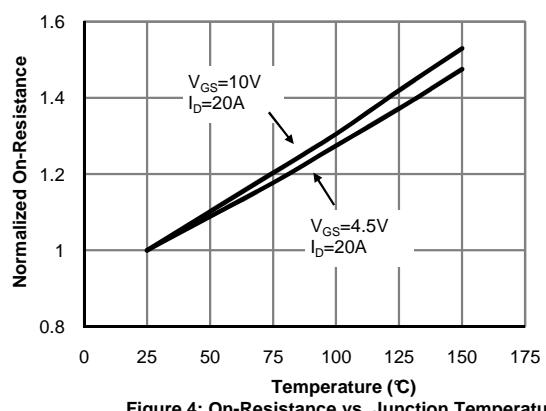
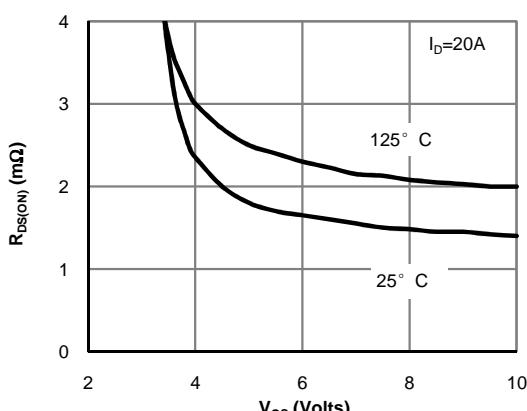
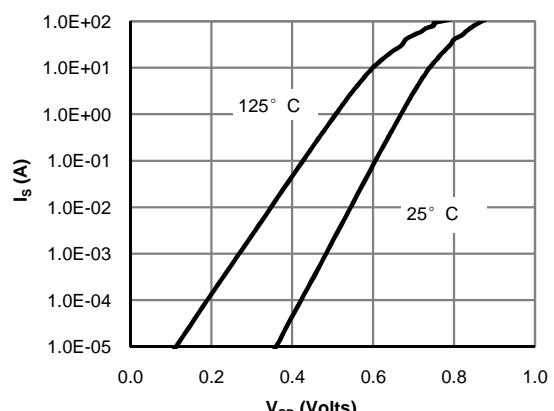
E. The static characteristics in Figures 1 to 6 are obtained using <300μs pulses, duty cycle 0.5% max.

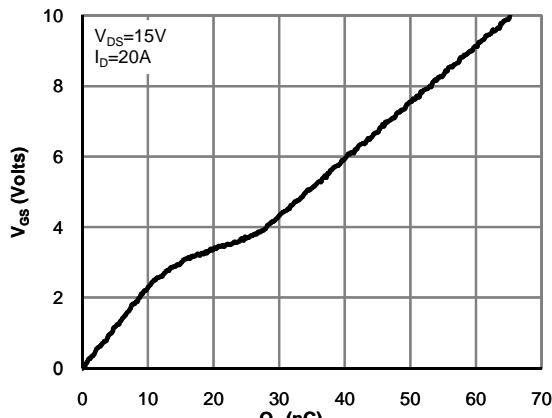
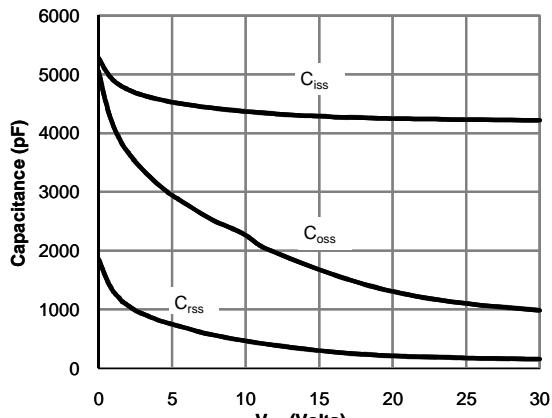
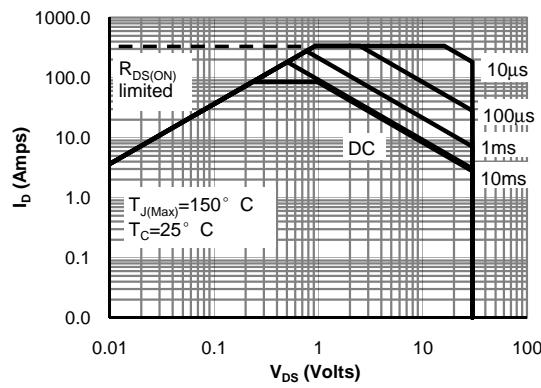
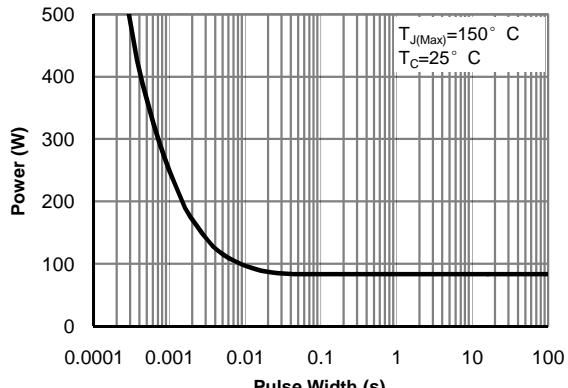
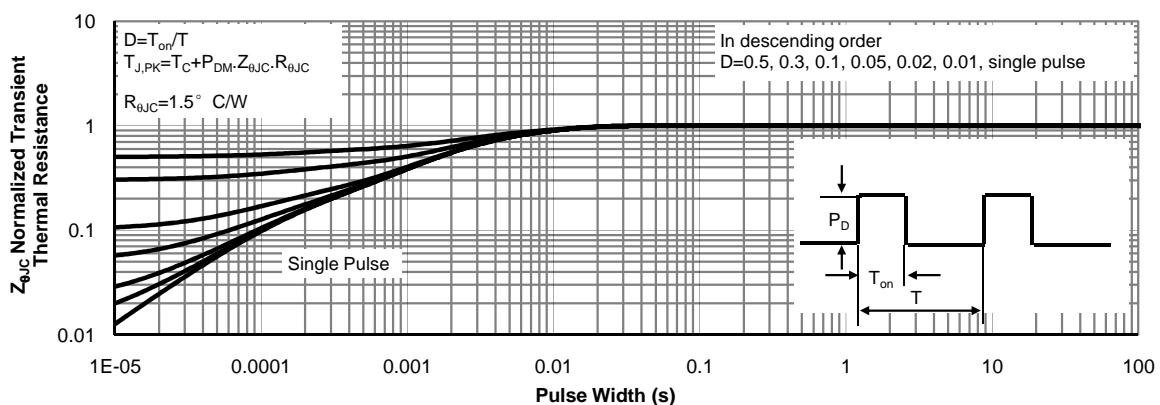
F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of  $T_{\text{J(MAX)}}=150^\circ\text{C}$ . The SOA curve provides a single pulse rating.

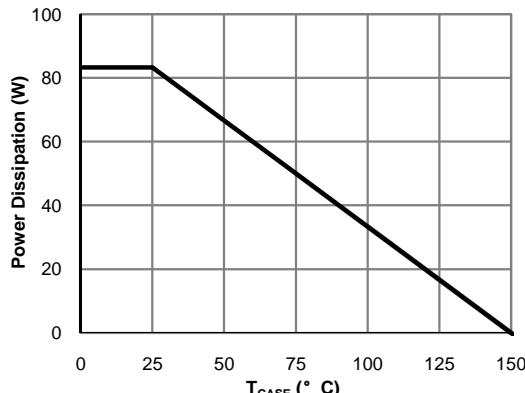
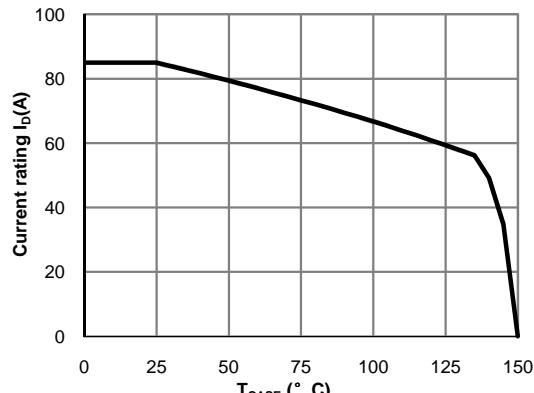
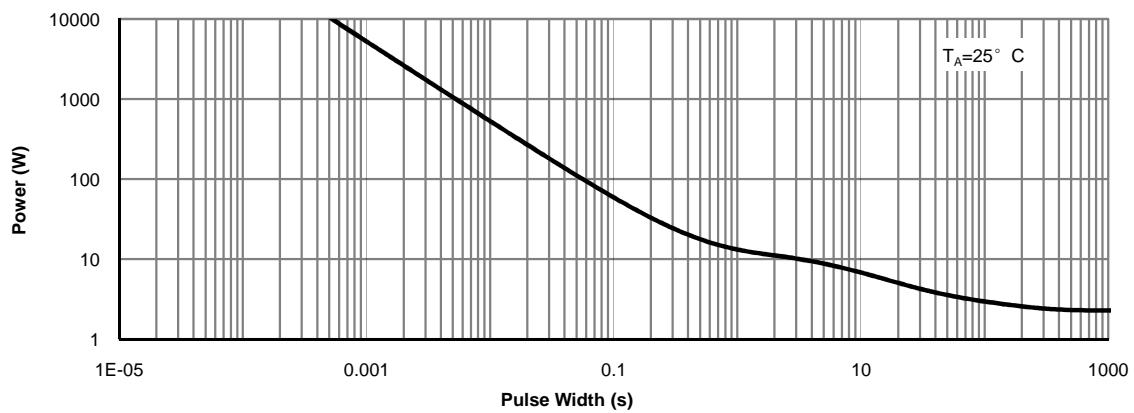
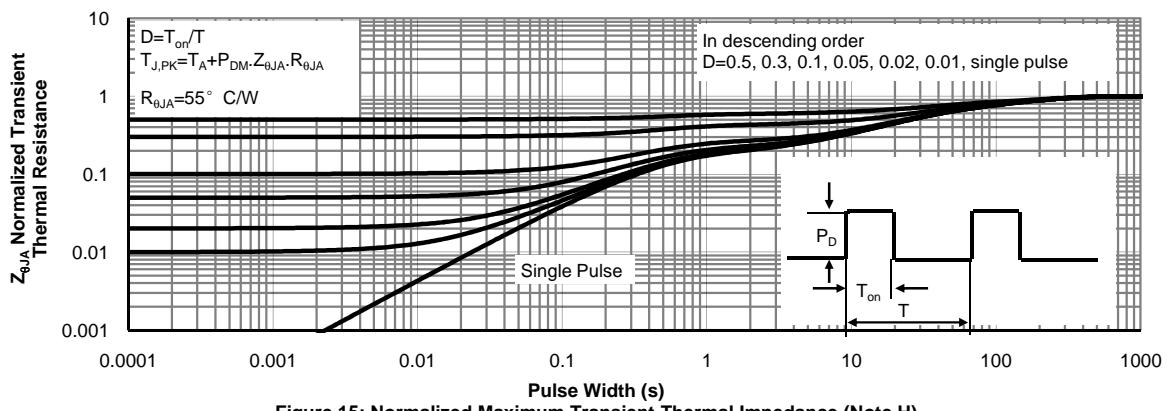
G. The maximum current rating is package limited.

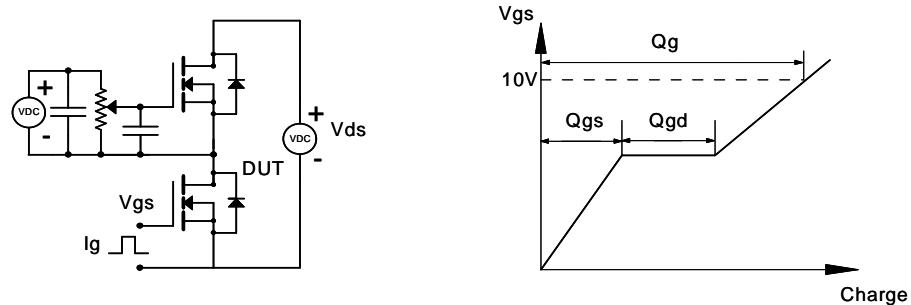
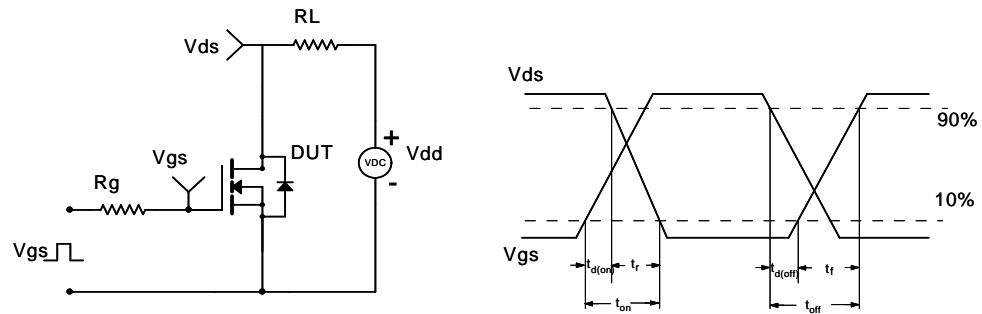
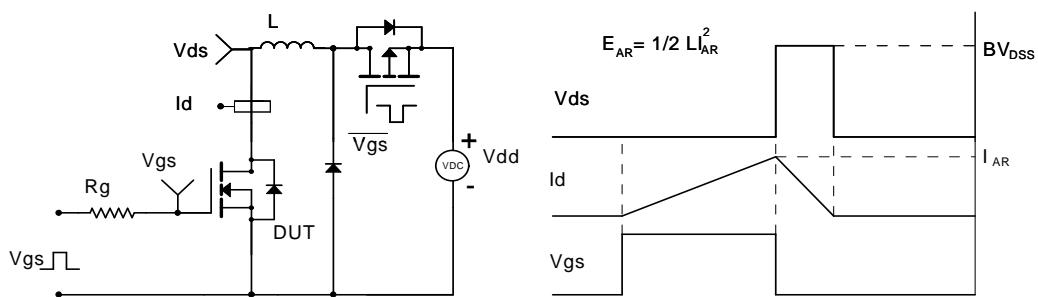
H. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ .

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**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

**Fig 1: On-Region Characteristics (Note E)**

**Figure 2: Transfer Characteristics (Note E)**

**Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)**

**Figure 4: On-Resistance vs. Junction Temperature (Note E)**

**Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)**

**Figure 6: Body-Diode Characteristics (Note E)**

**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

**Figure 7: Gate-Charge Characteristics**

**Figure 8: Capacitance Characteristics**

**Figure 9: Maximum Forward Biased Safe Operating Area (Note F)**

**Figure 10: Single Pulse Power Rating Junction-to-Case (Note F)**


**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

**Figure 12: Power Derating (Note F)**

**Figure 13: Current Derating (Note F)**

**Figure 14: Single Pulse Power Rating Junction-to-Ambient (Note H)**

**Figure 15: Normalized Maximum Transient Thermal Impedance (Note H)**

**Gate Charge Test Circuit & Waveform**

**Resistive Switching Test Circuit & Waveforms**

**Unclamped Inductive Switching (UIS) Test Circuit & Waveforms**

**Diode Recovery Test Circuit & Waveforms**
